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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/621,708	QIAN, XUEJUN	
Examiner	Art Unit	_
Tae H. Yoon	1714	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	11-8-04	7		
Inventor Search	s-9-06	z		
Inventor Sand	P-316	w		
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